

Single P Channel MOSFET

Features

- ★ Advanced Trench MOS Technology
- ★ 100% EAS Guaranteed
- ★ Green Device Available

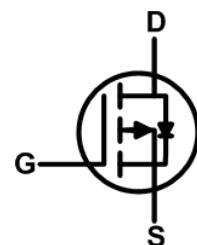
Applications

- ★ Power Management for Industrial DC / DC Converters.

Product Summary

| BVDSS | RDS(on) | ID |
|-------|---------|------|
| -100V | 95mΩ | -18A |

TO252 Pin Configuration



Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|---------------------------------------|---|------------|-------|
| V _{DS} | Drain-Source Voltage | -100 | V |
| V _{GS} | Gate-Source Voltage | ±20 | V |
| I _D @T _c =25°C | Continuous Drain Current, V _{GS} @ -10V ¹ | -18 | A |
| I _D @T _c =100°C | Continuous Drain Current, V _{GS} @ -10V ¹ | -12 | A |
| I _D @T _A =25°C | Continuous Drain Current, V _{GS} @ -10V ¹ | -3.5 | A |
| I _D @T _A =70°C | Continuous Drain Current, V _{GS} @ -10V ¹ | -2.8 | A |
| I _{DM} | Pulsed Drain Current ² | -75 | A |
| EAS | Single Pulse Avalanche Energy ³ | 157.2 | mJ |
| I _{AS} | Avalanche Current | 18.9 | A |
| P _D @T _c =25°C | Total Power Dissipation ⁴ | 54 | W |
| P _D @T _A =25°C | Total Power Dissipation ⁴ | 2 | W |
| T _{STG} | Storage Temperature Range | -55 to 150 | °C |
| T _J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Data

| Symbol | Parameter | Typ. | Max. | Unit |
|------------------|--|------|------|------|
| R _{θJA} | Thermal Resistance Junction-Ambient ¹ | --- | 62 | °C/W |
| R _{θJC} | Thermal Resistance Junction-Case ¹ | --- | 2.3 | °C/W |



Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|----------------------------|--|--|-------|------|-----------|------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{\text{GS}}=0\text{V}$, $I_D=-250\mu\text{A}$ | -100 | --- | --- | V |
| $\text{R}_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance ² | $V_{\text{GS}}=-10\text{V}$, $I_D=-10\text{A}$ | --- | 78 | 95 | $\text{m}\Omega$ |
| | | $V_{\text{GS}}=-4.5\text{V}$, $I_D=-8\text{A}$ | --- | 86 | 110 | |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{\text{GS}}=V_{\text{DS}}$, $I_D=-250\mu\text{A}$ | -1.55 | -1.8 | -2.5 | V |
| I_{DSS} | Drain-Source Leakage Current | $V_{\text{DS}}=-100\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^{\circ}\text{C}$ | --- | --- | -50 | μA |
| I_{GSS} | Gate-Source Leakage Current | $V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$ | --- | --- | ± 100 | nA |
| g_{fs} | Forward Transconductance | $V_{\text{DS}}=-10\text{V}$, $I_D=-10\text{A}$ | --- | 24 | --- | S |
| Q_g | Total Gate Charge | $V_{\text{DS}}=-50\text{V}$, $V_{\text{GS}}=-10\text{V}$, $I_D=-20\text{A}$ | --- | 44.5 | --- | nC |
| Q_{gs} | Gate-Source Charge | | --- | 9.13 | --- | |
| Q_{gd} | Gate-Drain Charge | | --- | 5.93 | --- | |
| $\text{T}_{\text{d(on)}}$ | Turn-On Delay Time | $V_{\text{DD}}=-50\text{V}$, $V_{\text{GS}}=-10\text{V}$, $R_G=3.3\Omega$, $I_D=-10\text{A}$ | --- | 12 | --- | ns |
| T_r | Rise Time | | --- | 27.4 | --- | |
| $\text{T}_{\text{d(off)}}$ | Turn-Off Delay Time | | --- | 79 | --- | |
| T_f | Fall Time | | --- | 53.6 | --- | |
| C_{iss} | Input Capacitance | $V_{\text{DS}}=-20\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$ | --- | 3029 | --- | pF |
| C_{oss} | Output Capacitance | | --- | 129 | --- | |
| C_{rss} | Reverse Transfer Capacitance | | --- | 76 | --- | |

Diode Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|------------------------|--|---|------|------|------|------|
| I_s | Continuous Source Current ^{1,5} | $V_G=V_D=0\text{V}$, Force Current | --- | --- | -18 | A |
| V_{SD} | Diode Forward Voltage ² | $V_{\text{GS}}=0\text{V}$, $\text{I}_s=1\text{A}$, $T_J=25^{\circ}\text{C}$ | --- | --- | -1.2 | V |
| t_{rr} | Reverse Recovery Time | $\text{I}_F=-8\text{A}$, $d\text{I}/dt=-100\text{A}/\mu\text{s}$, | --- | 38.7 | --- | nS |
| | | $T_J=25^{\circ}\text{C}$ | --- | 22.4 | --- | nC |

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
3. The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=-25\text{V}$, $V_{\text{GS}}=-10\text{V}$, $L=0.88\text{mH}$, $\text{I}_{\text{AS}}=-18.9\text{A}$
4. The power dissipation is limited by 150°C junction temperature
5. The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

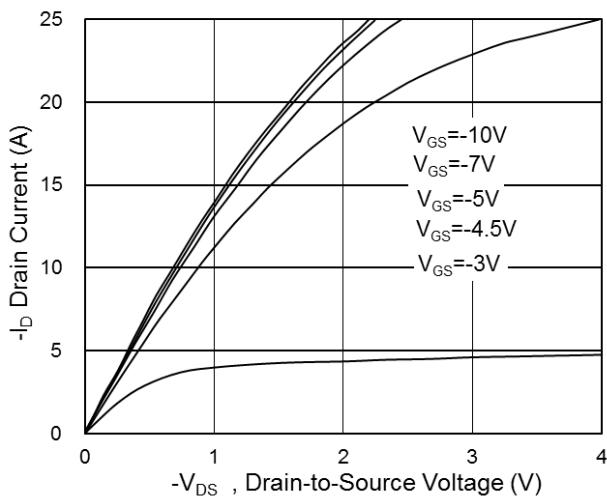


Fig.1 Typical Output Characteristics

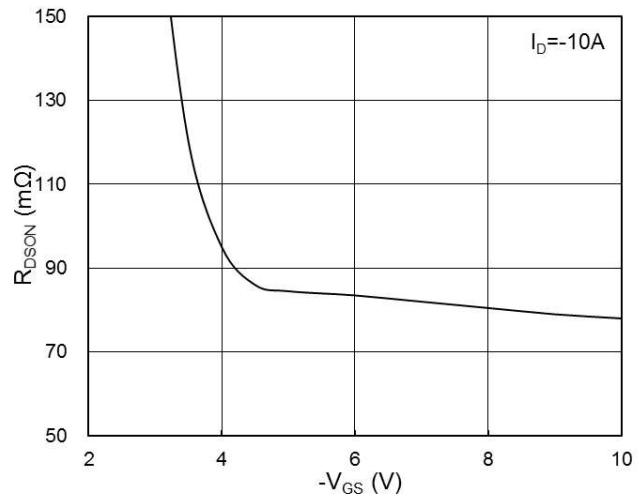


Fig.2 On-Resistance vs. G-S Voltage

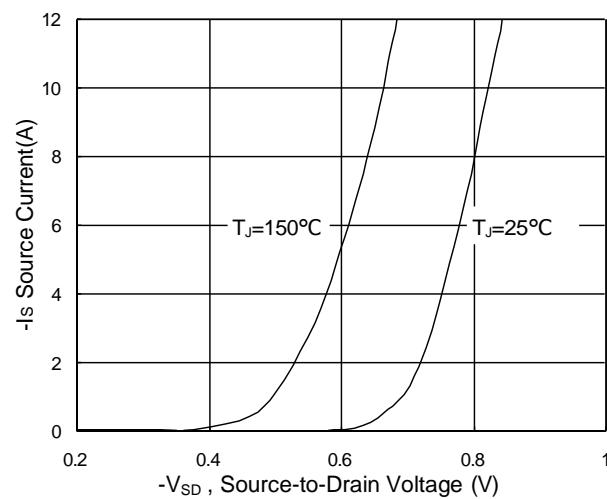


Fig.3 Typical S-D Diode Forward Voltage

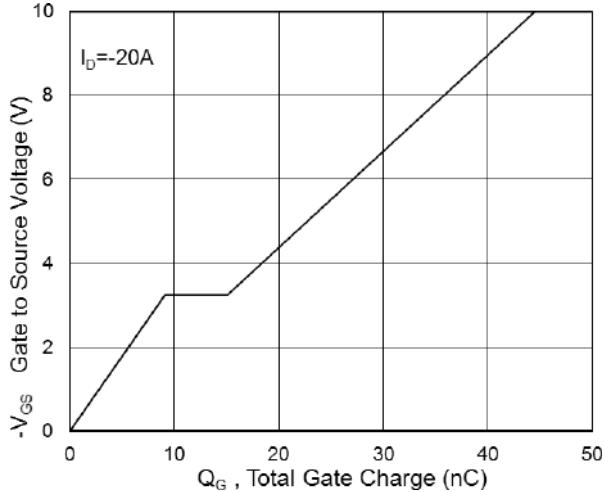


Fig.4 Gate-Charge Characteristics

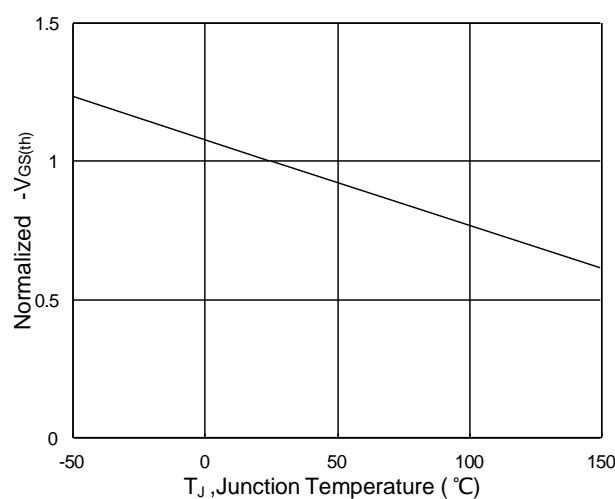


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

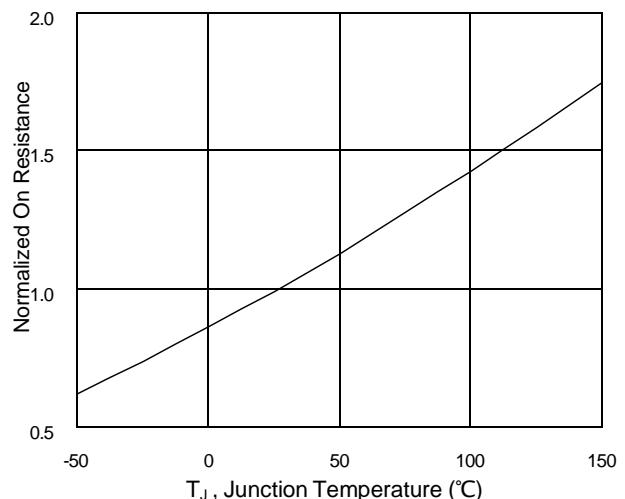


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

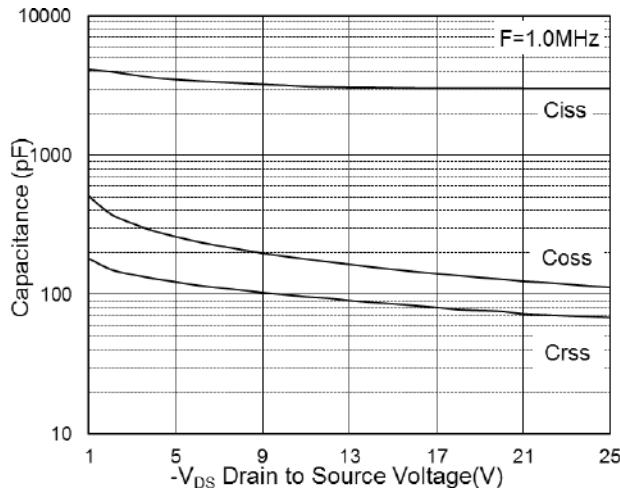


Fig.7 Capacitance

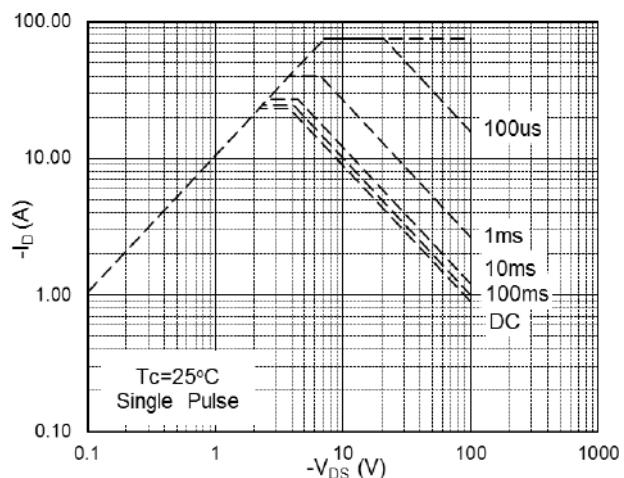


Fig.8 Safe Operating Area

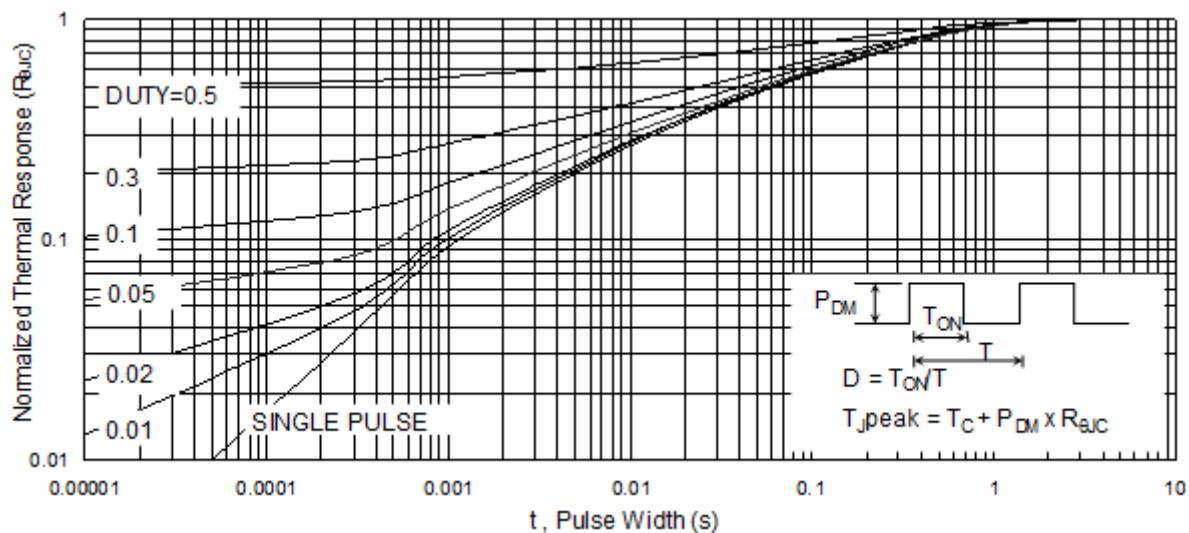


Fig.9 Normalized Maximum Transient Thermal Impedance

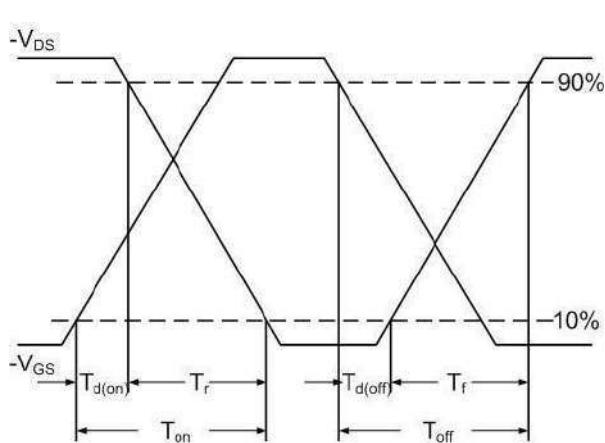


Fig.10 Switching Time Waveform

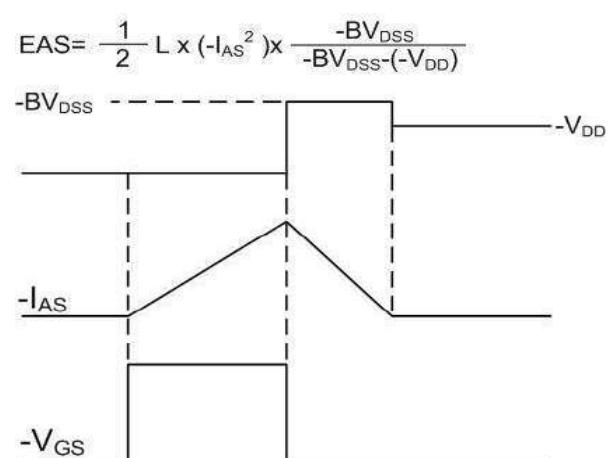
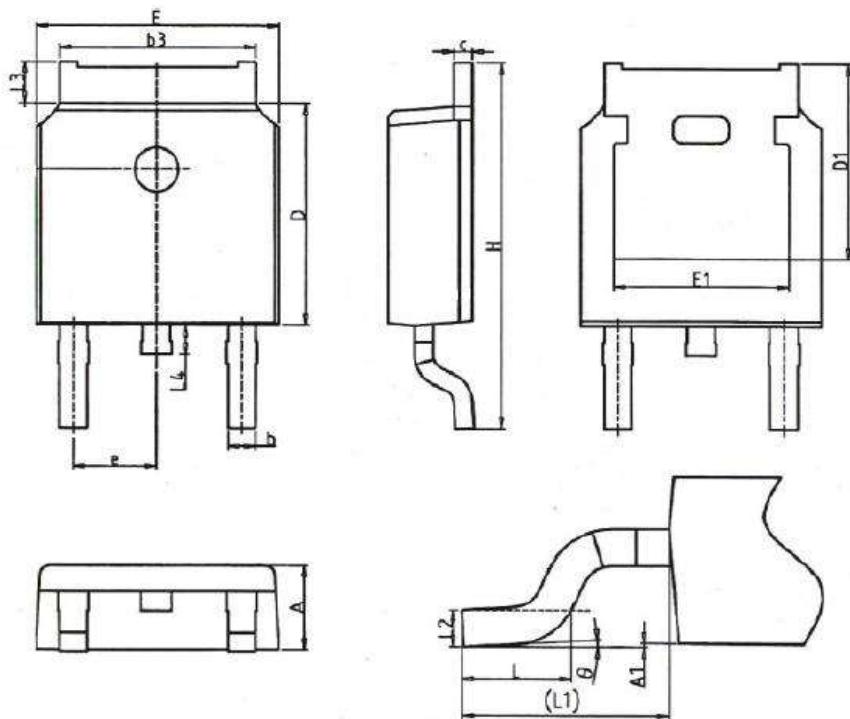


Fig.11 Unclamped Inductive Waveform

TO252 Package Outline



| SYMBOLS | MILLIMETERS | | INCHES | |
|----------|-------------|------|----------|-------|
| | MIN | MAX | MIN | MAX |
| A | 2.18 | 2.40 | 0.086 | 0.095 |
| A1 | - | 0.2 | - | 0.008 |
| b | 0.68 | 0.9 | 0.026 | 0.036 |
| b3 | 4.95 | 5.46 | 0.194 | 0.215 |
| c | 0.43 | 0.89 | 0.017 | 0.035 |
| D | 5.97 | 6.22 | 0.235 | 0.245 |
| D1 | 5.300REF | | 0.209REF | |
| E | 6.35 | 6.73 | 0.250 | 0.265 |
| E1 | 4.32 | -- | 0.170 | - |
| e | 2.286BSC | | 0.09BSC | |
| H | 9.4 | 10.5 | 0.370 | 0.413 |
| L | 1.38 | 1.78 | 0.054 | 0.070 |
| L1 | 2.90REF | | 0.114REF | |
| L2 | 0.51BSC | | 0.020BSC | |
| L3 | 0.88 | 1.28 | 0.034 | 0.050 |
| L4 | 0.5 | 1 | 0.019 | 0.039 |
| Θ | 0° | 8° | 0° | 8° |

